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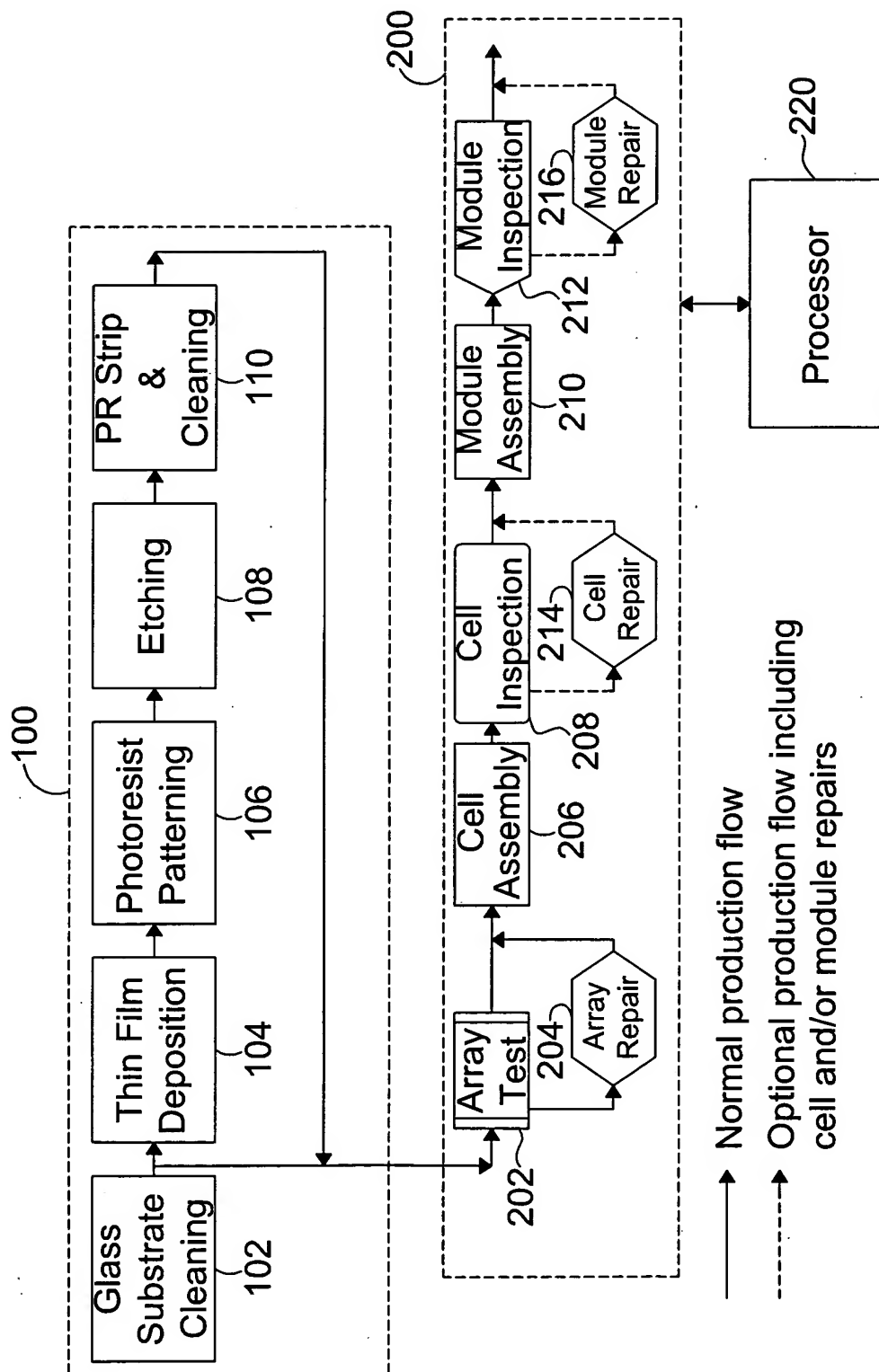


FIG. 1A

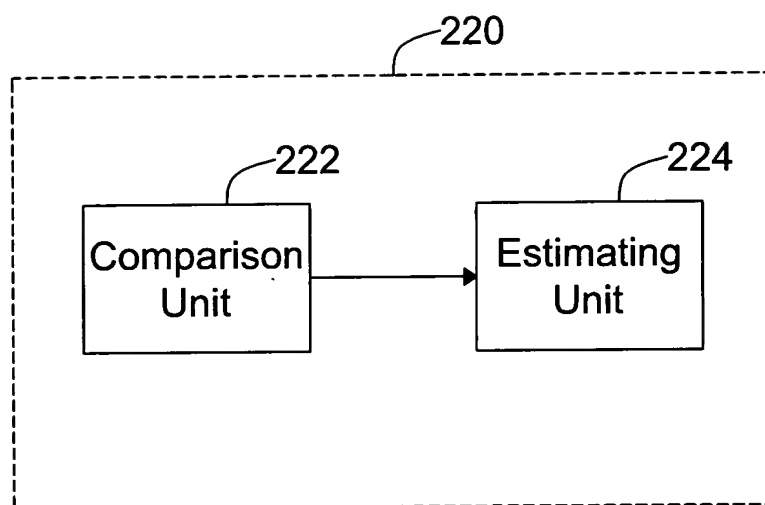


FIG. 1B

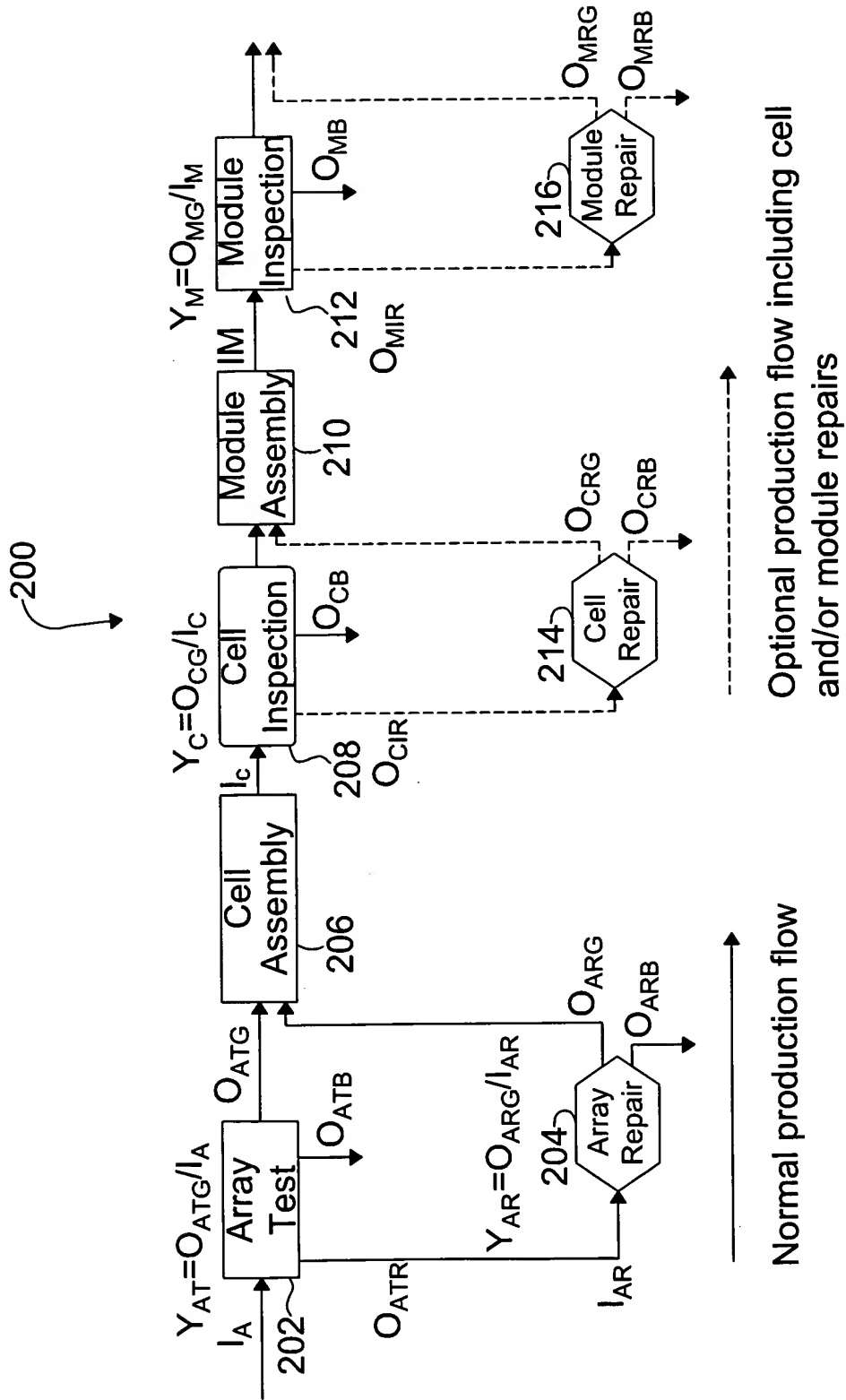


FIG. 2

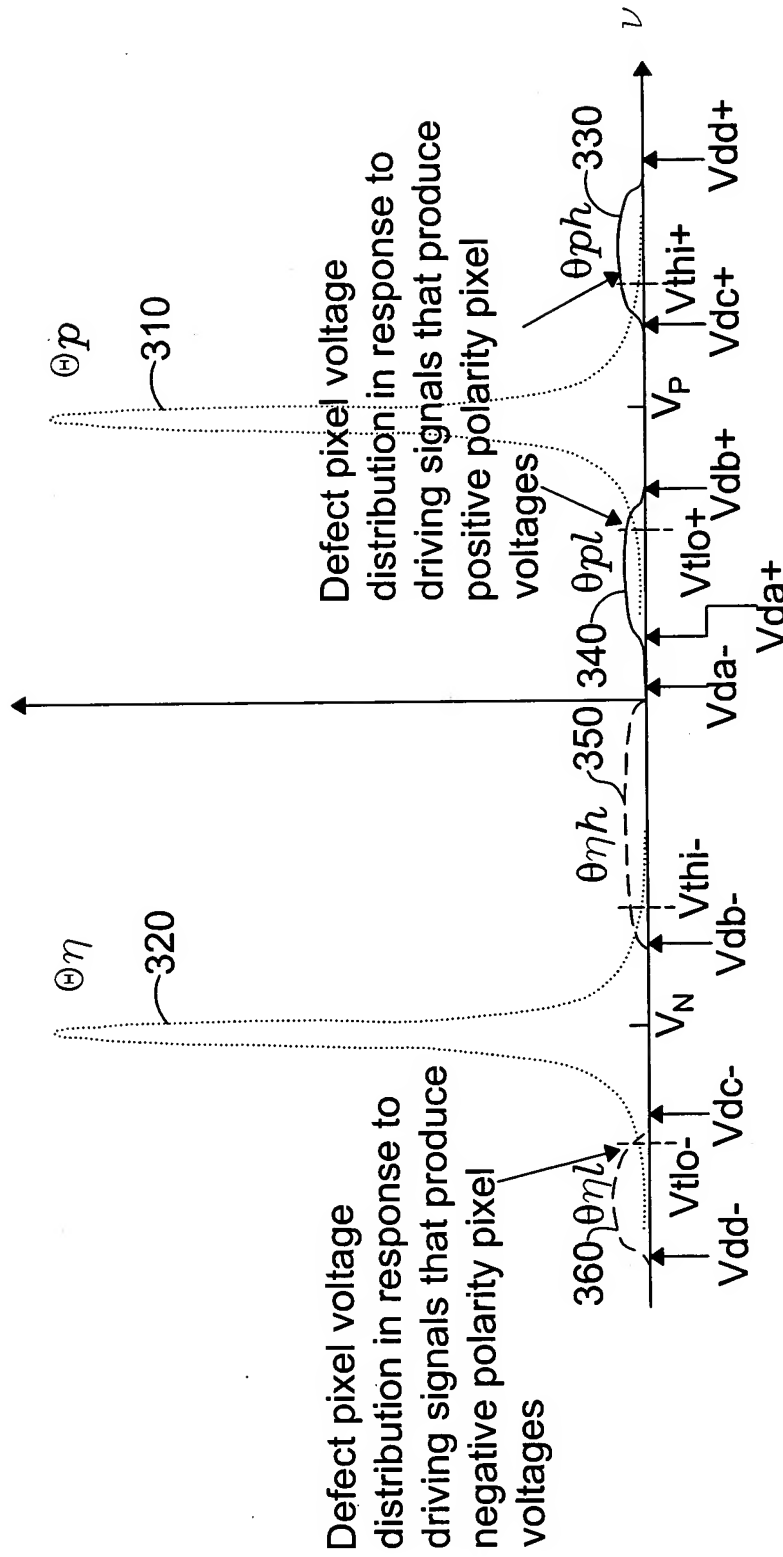


FIG. 3A

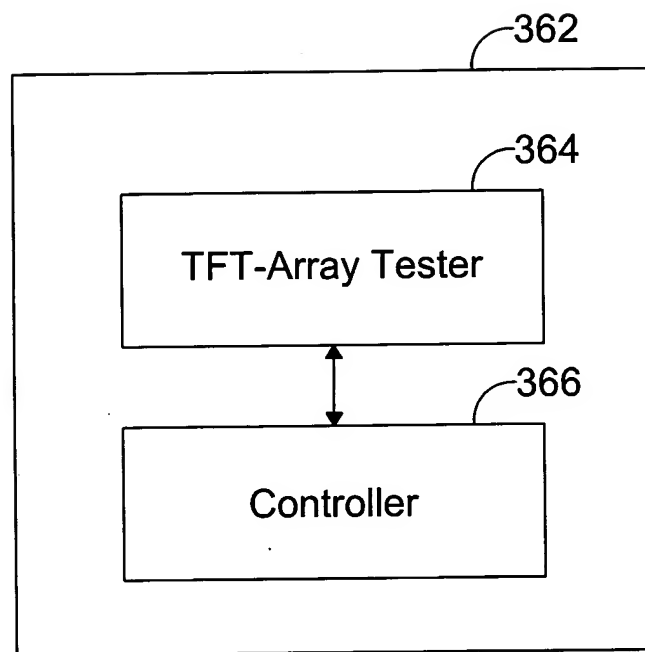


FIG. 3B

(1) Sensor measurement with small standard deviation, σ_p .

(2) Sensor measurement with large standard deviation, σ_p .

Defective pixels in this region are not detected by TFT-array tester and become under-killed defects.

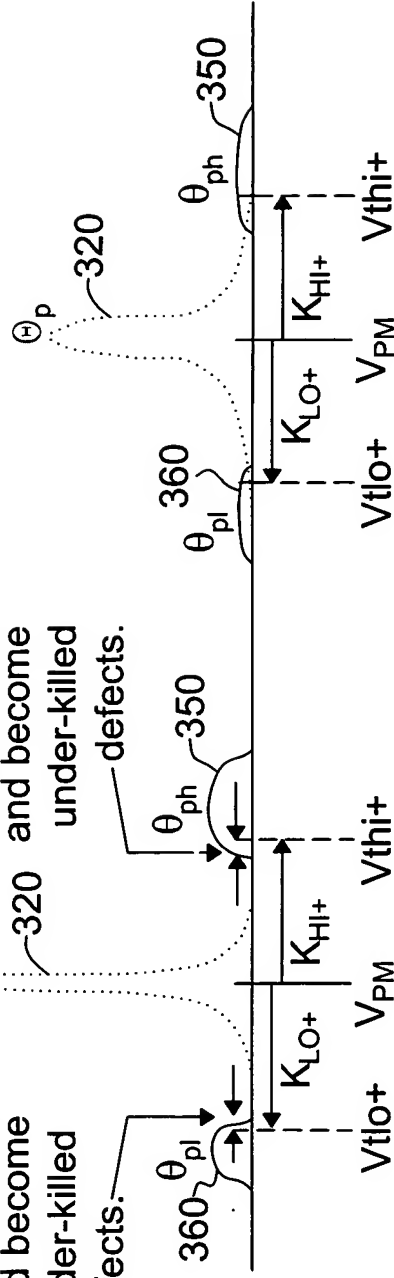


FIG. 3C

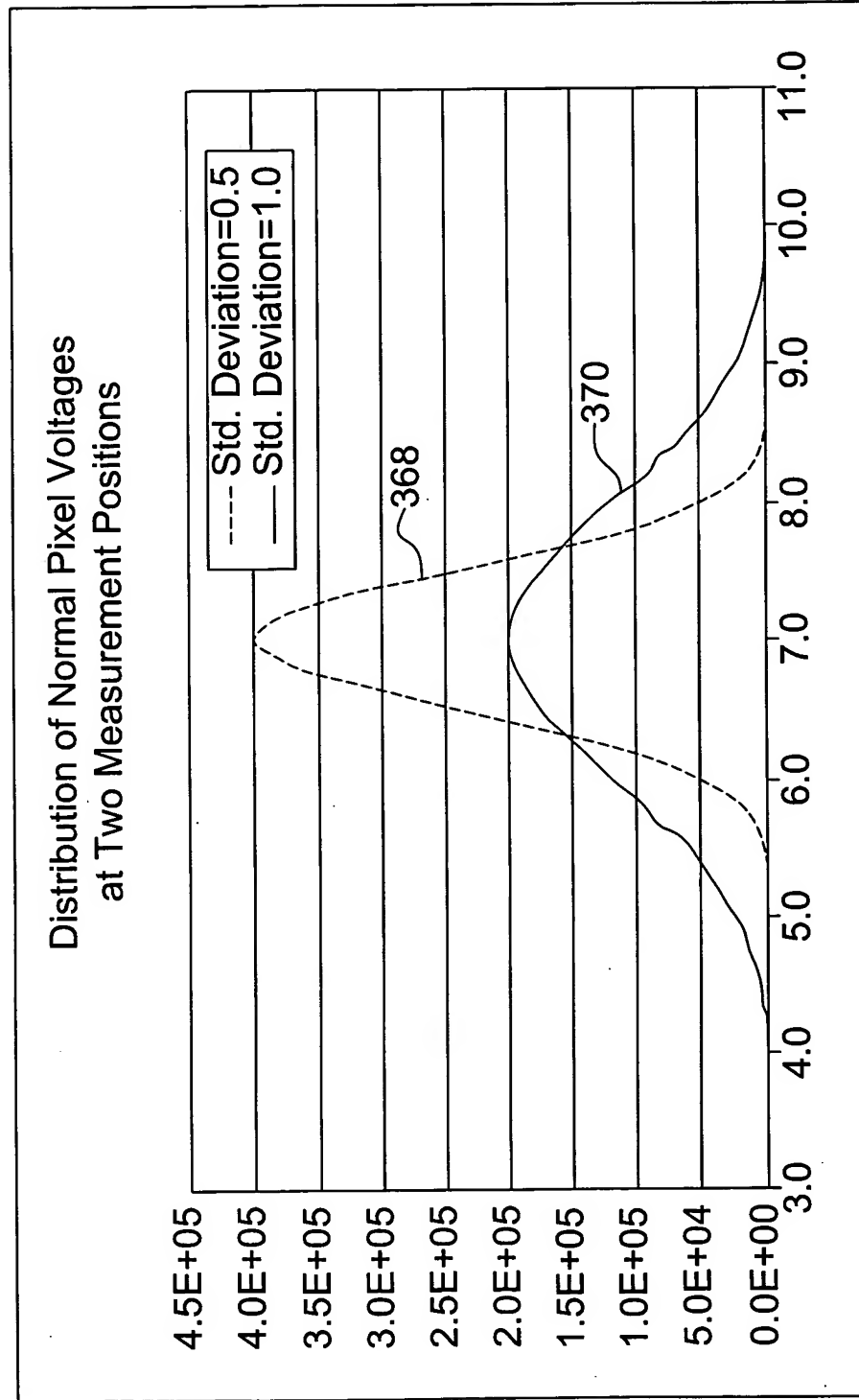


FIG. 3D

- (1) Sensor measurement with small standard deviation, σ_p .
- (2) Sensor measurement with large standard deviation, σ_p .

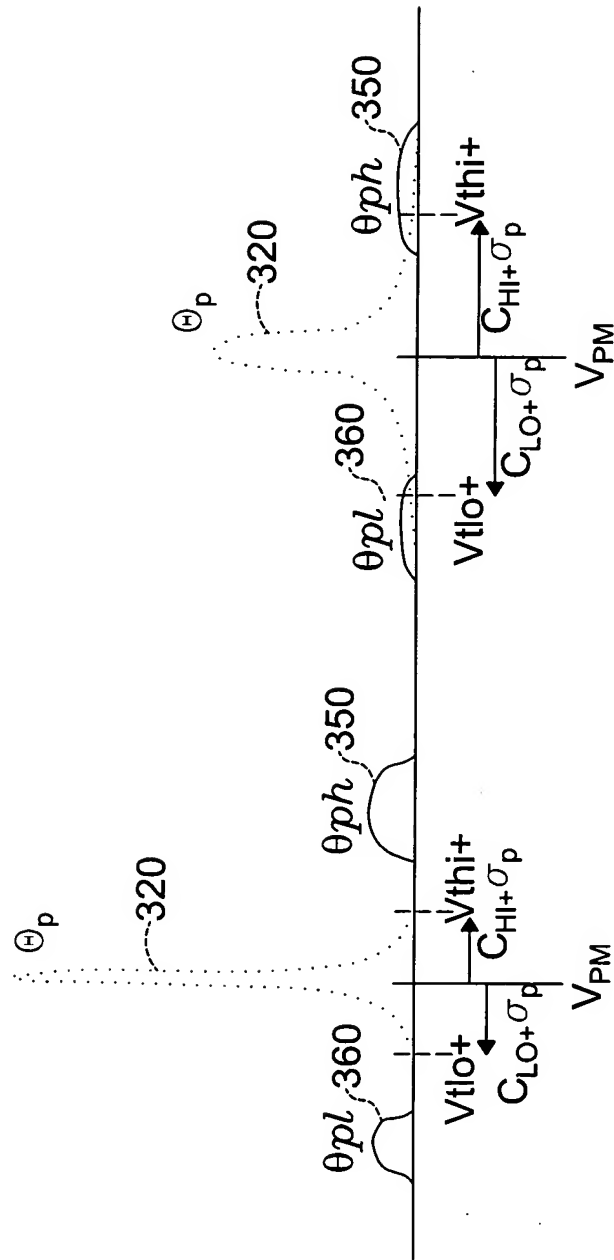


FIG. 3E

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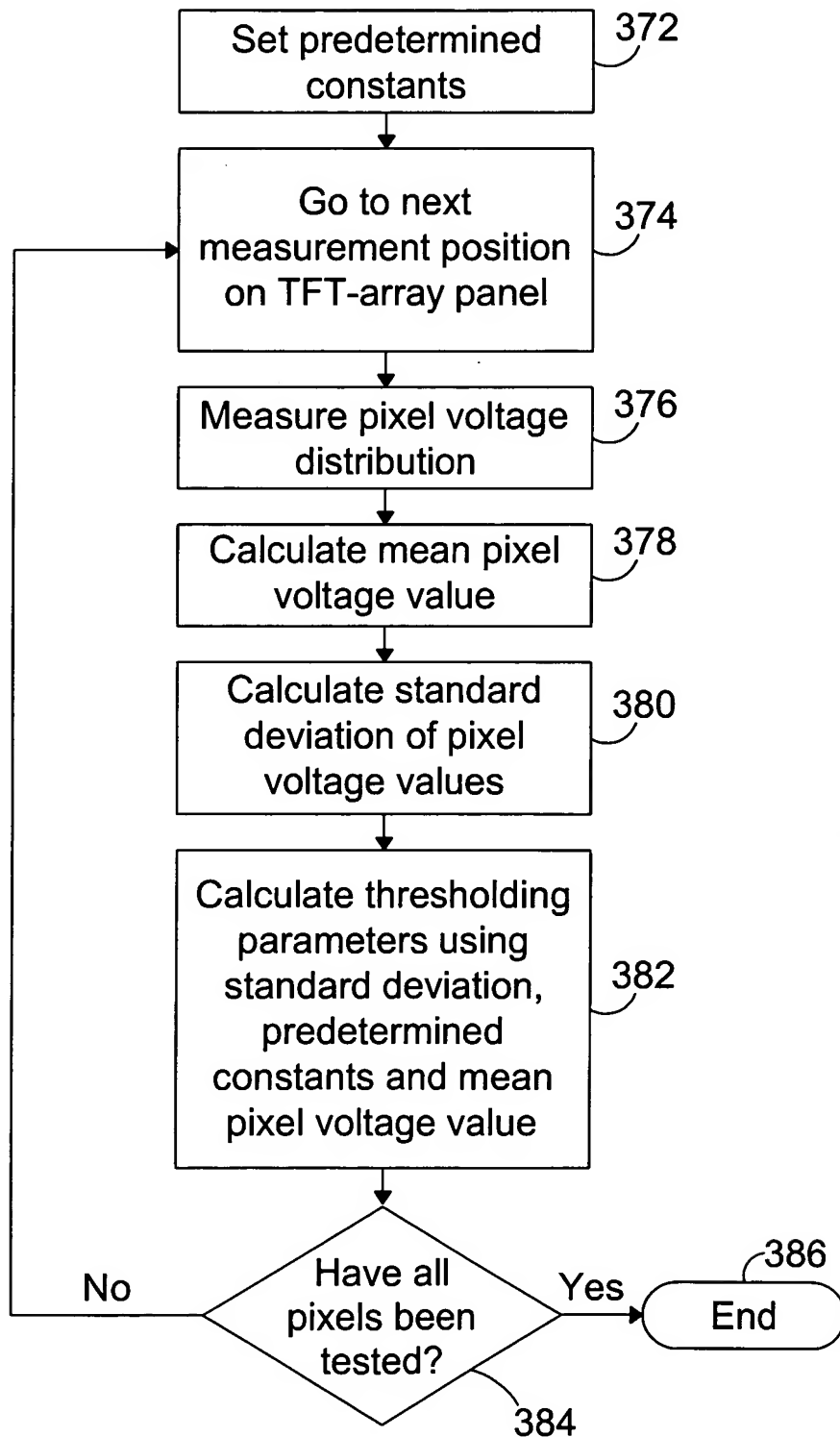


FIG. 3F

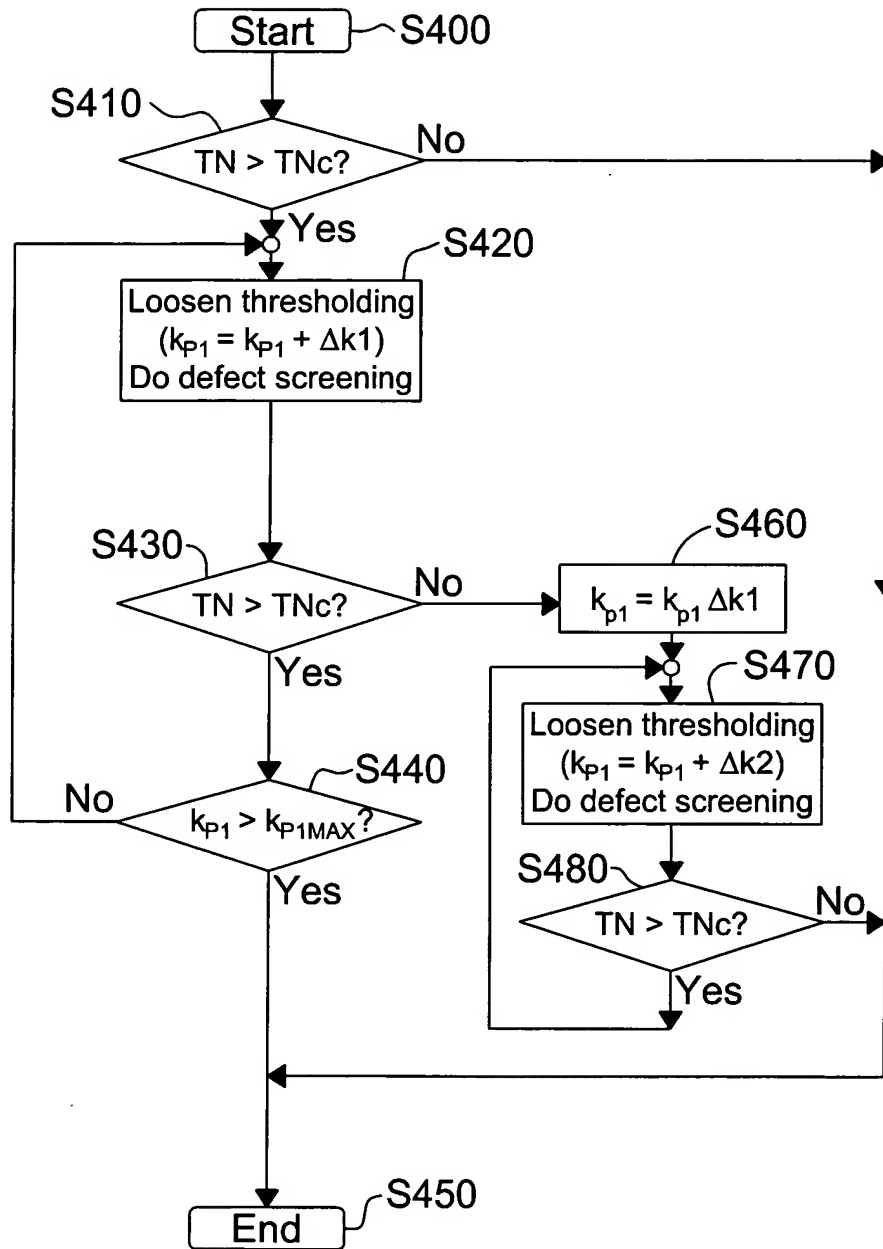


FIG. 4